FAIRCHILD

SEMICONDUCTOR IM

NDS9959 Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulses in the avalanche and commutation modes. These devices are particularly suited for low voltage applications such as DC motor control and DC/DC conversion where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- 2.0A, 50V. R_{DS(ON)} = 0.3Ω @ V_{GS} = 10V
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.

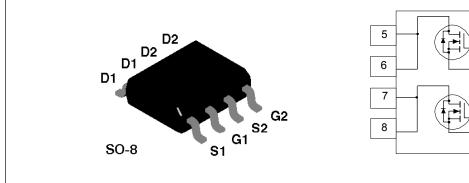
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Dual MOSFET in surface mount package.



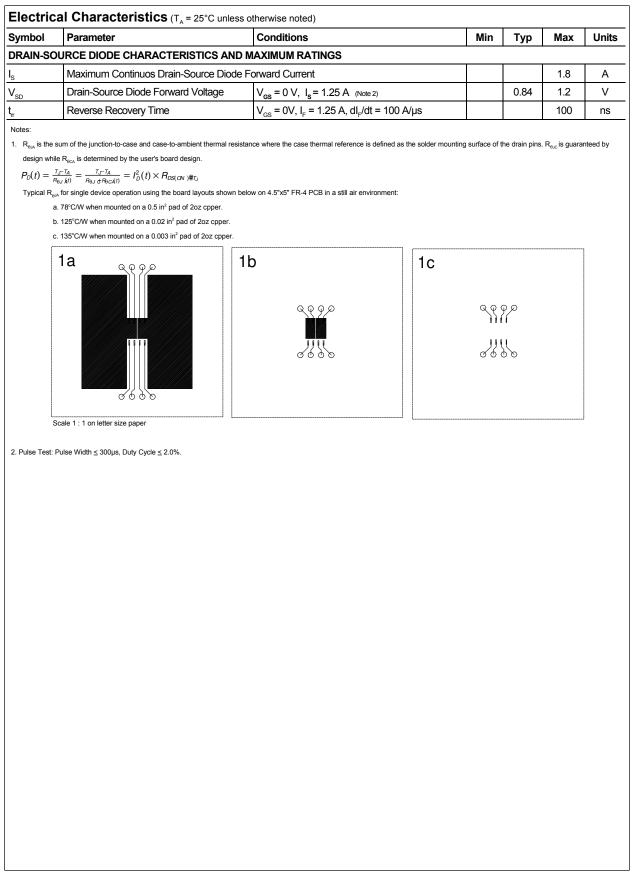
Absolute Maximum Ratings T_A = 25°C unless otherwise noted

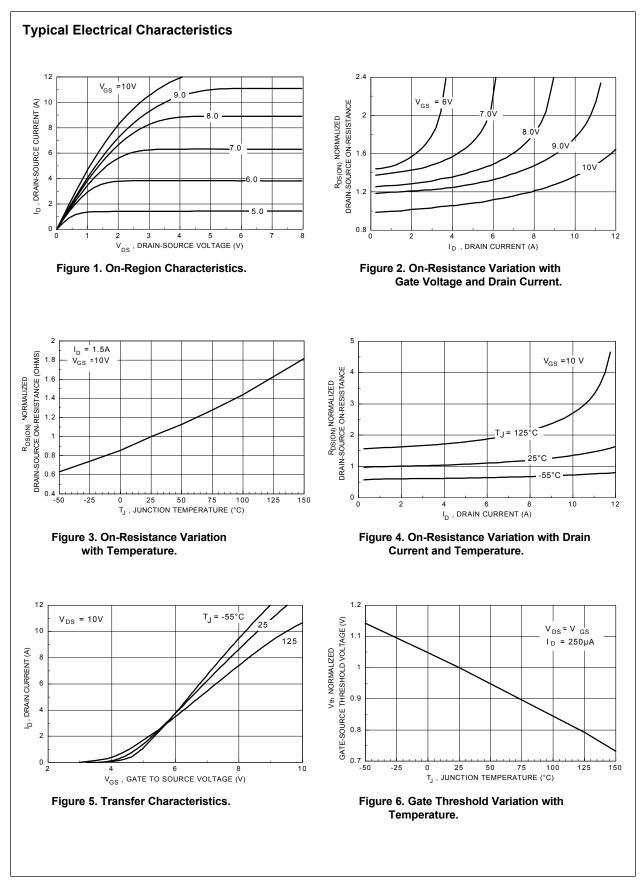
Symbol	Parameter		NDS9959	Units	
V _{DSS}	Drain-Source Voltage		50	V	
V _{GSS}	Gate-Source Voltage		± 20	V	
l _D	Drain Current - Continuous @ $T_A = 25^{\circ}C$	(Note 1a)	± 2.0	А	
	- Continuous @ T _A = 70°C	(Note 1a)	± 1.6		
	- Pulsed (a) $T_A = 25^{\circ}C$	Ī	± 8		
P _D	Power Dissipation for Dual Operation		2	W	
	Power Dissipation for Single Operation	(Note 1a)	1.6		
		(Note 1b)	1		
		(Note 1c)	0.9		
Γ _J ,T _{stg}	Operating and Storage Temperature Range		-55 to 150	°C	
THERMA	L CHARACTERISTICS				
R _{eja}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W	
۲ _{өлс}	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W	

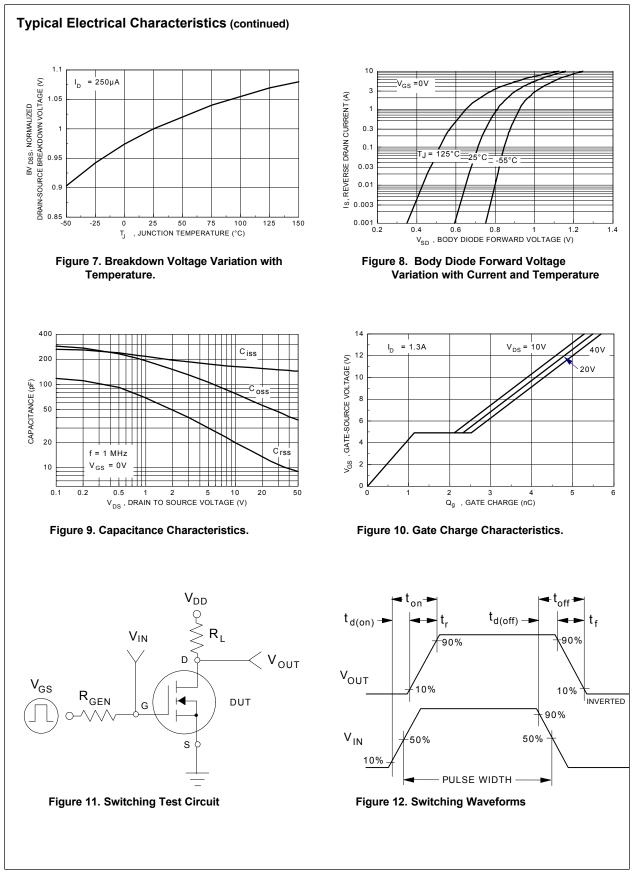
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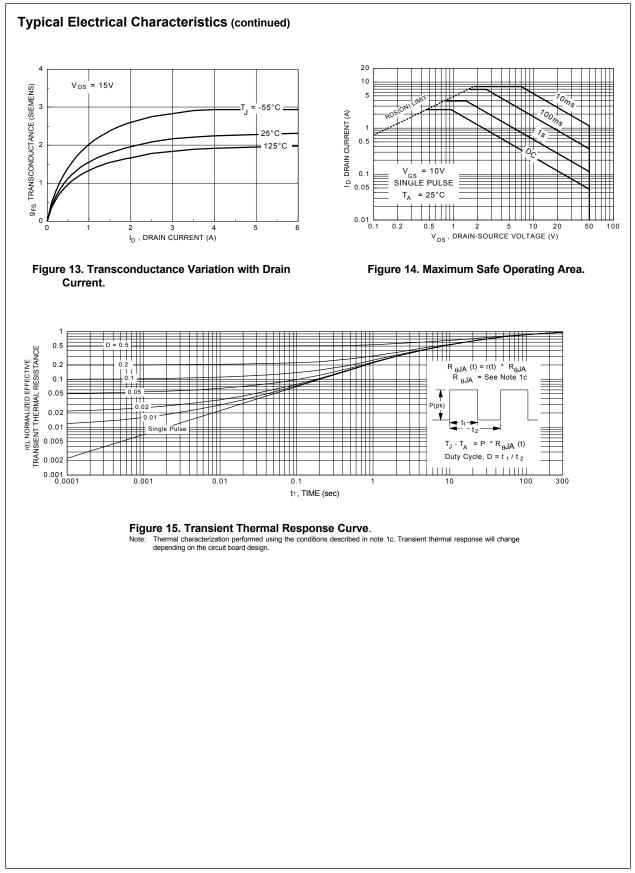
Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{gs} = 0 V, I _p = 250 μA		50			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 40 V, V _{GS} = 0 V				2	μA
			T_= 55°C			25	μA
GSSF	Gate - Body Leakage, Forward	V _{gs} = 20 V, V _{ps} = 0 V				100	nA
GSSR	Gate - Body Leakage, Reverse	V _{gs} = -20 V, V _{ps} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note2)				1		
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	$V_{ps} = V_{qs}$, $I_{p} = 250 \ \mu A$		3	4	V
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{gs} = 10 V, I_p = 1.5 A$				0.3	Ω
		$V_{gs} = 5 V, I_{p} = 0.6 A$				0.5	
D(on)	On-State Drain Current	$V_{GS} = 10 V, V_{DS} = 5 V$		8			Α
9 _{FS}	Forward Transconductance	V _{ps} = 15 V, I _p = 2.0 A		1	2.7		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{\text{DS}} = 25 \text{ V}, V_{\text{GS}} = 0 \text{ V},$ f = 1.0 MHz			152	250	pF
C _{oss}	Output Capacitance				50	85	pF
C _{rss}	Reverse Transfer Capacitance				12	25	pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
D(on)	Turn - On Delay Time	$V_{DD} = 30 \text{ V}, I_{D} = 0.6 \text{ A},$			4	40	ns
т	Tum - On Rise Time	$V_{GS} = 10 \text{ V}, \text{ R}_{L} = 50 \Omega,$			8	70	ns
D(off)	Turn - Off Delay Time	$R_{GEN} = 6 \Omega$			9	100	ns
f	Turn - Off Fall Time				11	70	ns
ຊູ	Total Gate Charge	$V_{DS} = 25 V,$ $I_{D} = 1.3 A, V_{GS} = 10 V$			4.3	15	nC
Q _{gs}	Gate-Source Charge				1.1		nC
Q _{gd}	Gate-Drain Charge				1.5		nC







NDS9959.SAM



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